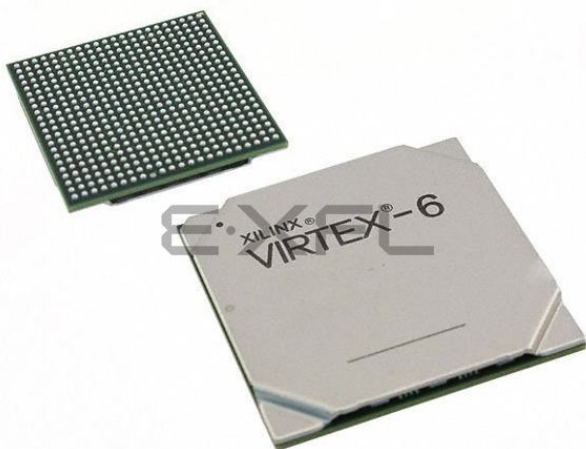




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Understanding [Embedded - FPGAs \(Field Programmable Gate Array\)](#)

Embedded - FPGAs, or Field Programmable Gate Arrays, are advanced integrated circuits that offer unparalleled flexibility and performance for digital systems. Unlike traditional fixed-function logic devices, FPGAs can be programmed and reprogrammed to execute a wide array of logical operations, enabling customized functionality tailored to specific applications. This reprogrammability allows developers to iterate designs quickly and implement complex functions without the need for custom hardware.

Applications of Embedded - FPGAs

The versatility of Embedded - FPGAs makes them indispensable in numerous fields. In telecommunications.

Details

Product Status	Active
Number of LABs/CLBs	15600
Number of Logic Elements/Cells	199680
Total RAM Bits	12681216
Number of I/O	400
Number of Gates	-
Voltage - Supply	0.95V ~ 1.05V
Mounting Type	Surface Mount
Operating Temperature	0°C ~ 85°C (TJ)
Package / Case	784-BBGA, FCBGA
Supplier Device Package	784-FCBGA (29x29)
Purchase URL	https://www.e-xfl.com/product-detail/xilinx/xc6vcx195t-2ffg784c

Virtex-6 CXT FPGA Feature Summary

Table 1: Virtex-6 CXT FPGA Feature Summary by Device

Device	Logic Cells	Configurable Logic Blocks (CLBs)		DSP48E1 Slices ⁽²⁾	Block RAM Blocks			MMCMs ⁽⁴⁾	Interface Blocks for PCI Express	Ethernet MACs ⁽⁵⁾	Maximum GTX Transceivers	Total I/O Banks ⁽⁶⁾	Max User I/O ⁽⁷⁾
		Slices ⁽¹⁾	Max Distributed RAM (Kb)		18 Kb ⁽³⁾	36 Kb	Max (Kb)						
XC6VCX75T	74,496	11,640	1,045	288	312	156	5,616	6	1	1	12	9	360
XC6VCX130T	128,000	20,000	1,740	480	528	264	9,504	10	2	1	16	15	600
XC6VCX195T	199,680	31,200	3,040	640	688	344	12,384	10	2	1	16	15	600
XC6VCX240T	241,152	37,680	3,650	768	832	416	14,976	12	2	1	16	18	600

Notes:

- Each Virtex-6 CXT FPGA slice contains four LUTs and eight flip-flops, only some slices can use their LUTs as distributed RAM or SRLs.
- Each DSP48E1 slice contains a 25 x 18 multiplier, an adder, and an accumulator.
- Block RAMs are fundamentally 36 Kbits in size. Each block can also be used as two independent 18 Kb blocks.
- Each CMT contains two mixed-mode clock managers (MMCM).
- This table lists individual Ethernet MACs per device.
- Does not include configuration Bank 0.
- This number does not include GTX transceivers.

Virtex-6 CXT FPGA Device-Package Combinations and Maximum I/Os

Virtex-6 CXT FPGA package combinations with the maximum available I/Os per package are shown in Table 2.

Table 2: Virtex-6 CXT FPGA Device-Package Combinations and Maximum Available I/Os

Package	FF484 FFG484		FF784 FFG784		FF1156 FFG1156	
Size (mm)	23 x 23		29 x 29		35 x 35	
Device	GTs	I/O	GTs	I/O	GTs	I/O
XC6VCX75T	8 GTXs	240	12 GTXs	360		
XC6VCX130T	8 GTXs	240	12 GTXs	400	16 GTXs	600
XC6VCX195T			12 GTXs	400	16 GTXs	600
XC6VCX240T			12 GTXs	400	16 GTXs	600

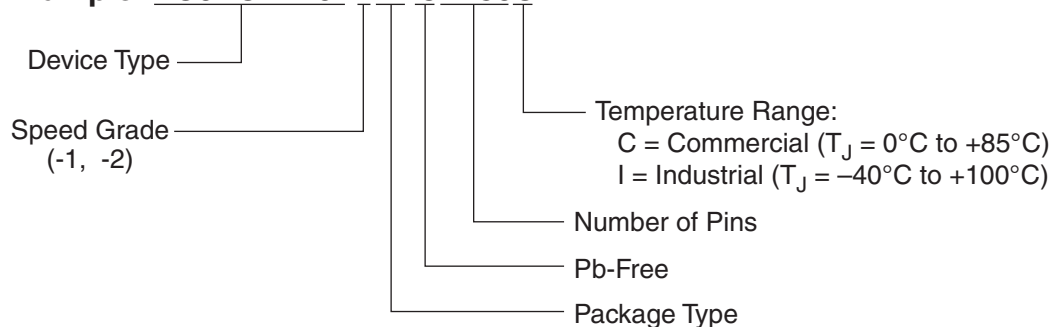
Notes:

- Flip-chip packages are also available in Pb-Free versions (FFG).

Virtex-6 CXT FPGA Ordering Information

The Virtex-6 CXT FPGA ordering information shown in Figure 1 applies to all packages including Pb-Free.

Example: XC6VCX240T-1FFG1156C



DS153_01_062109

Figure 1: Virtex-6 CXT FPGA Ordering Information

Table 8: Available I/O Pin/Device/Package Combinations

Virtex-6 CXT Device	User I/O Pins	Virtex-6 CXT FPGA Package		
		FF484	FF784	FF1156
XC6VCX75T	Available User I/Os	240	360	–
	Differential I/O Pairs	120	180	–
XC6VCX130T	Available User I/Os	240	400	600
	Differential I/O Pairs	120	200	300
XC6VCX195T	Available User I/Os	–	400	600
	Differential I/O Pairs	–	200	300
XC6VCX240T	Available User I/Os	–	400	600
	Differential I/O Pairs	–	200	300

GTX Transceivers in CXT Devices

CXT devices have between 8 to 16 gigabit transceiver circuits. Each GTX transceiver is a combined transmitter and receiver capable of operating at a data rate between 480 Mb/s and 3.75 Gb/s. Lower data rates can be achieved using FPGA logic-based oversampling. The transmitter and receiver are independent circuits that use separate PLLs to multiply the reference frequency input by certain programmable numbers between 2 and 25, to become the bit-serial data clock. Each GTX transceiver has a large number of user-definable features and parameters. All of these can be defined during device configuration, and many can also be modified during operation.

FF1156 Package Placement Diagrams

Figure 7 through Figure 10 show the placement diagrams for the GTX transceivers in the FF1156 package.

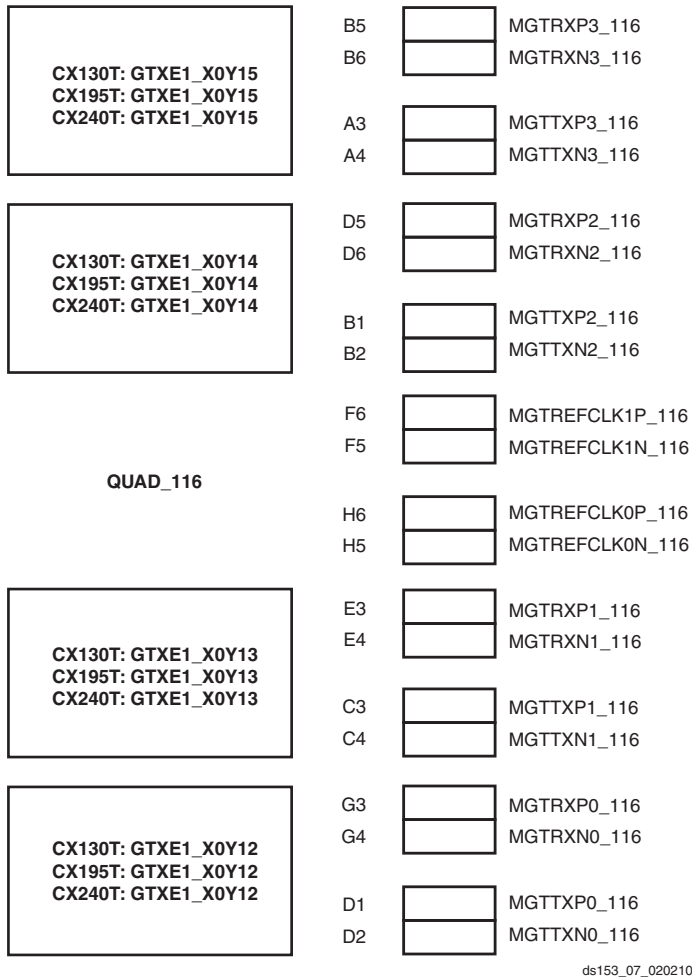


Figure 7: Placement Diagram for the FF1156 Package
(1 of 4)

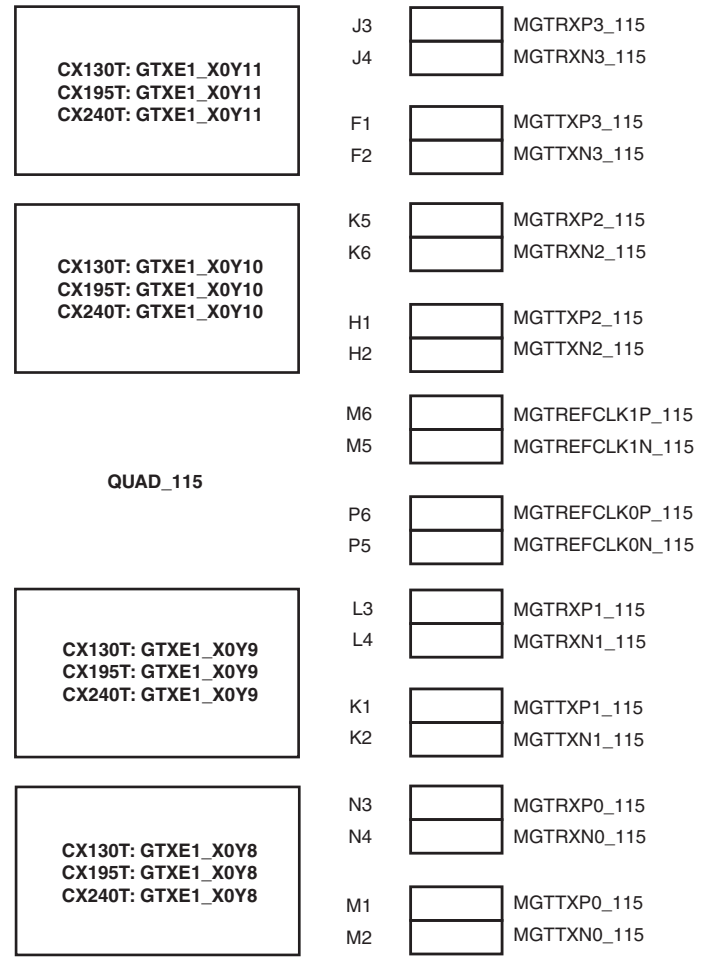


Figure 8: Placement Diagram for the FF1156 Package
(2 of 4)

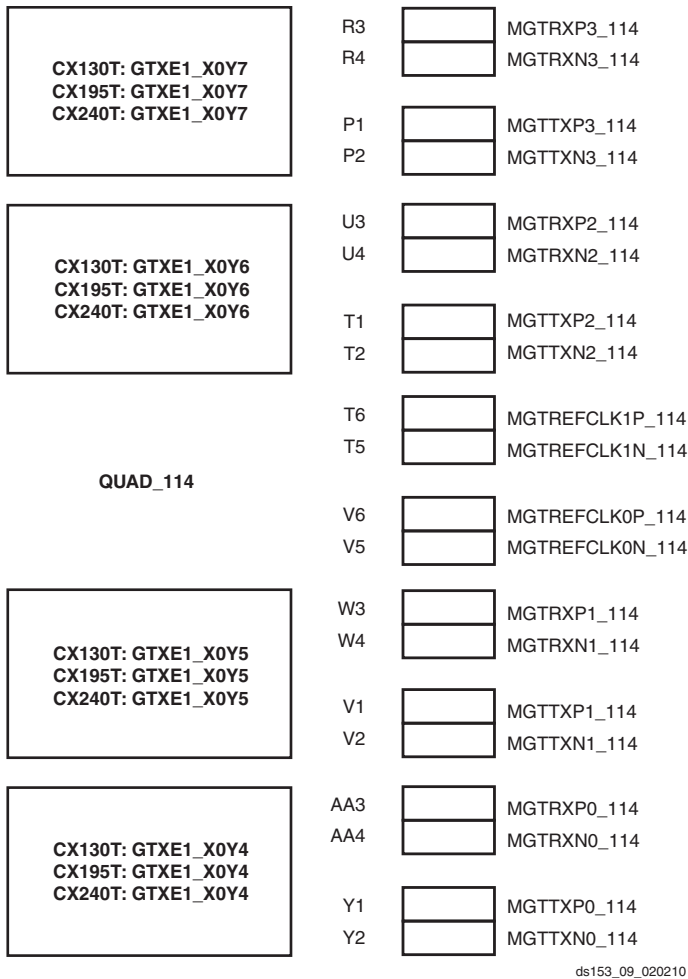


Figure 9: Placement Diagram for the FF1156 Package
(3 of 4)

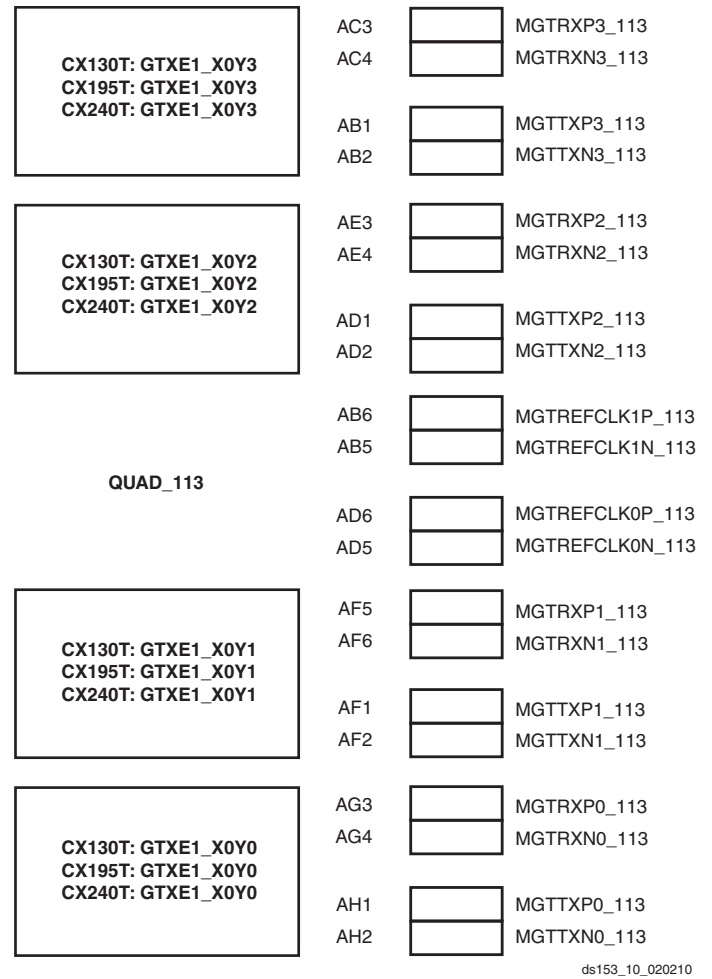


Figure 10: Placement Diagram for the FF1156 Package
(4 of 4)

Table 10: Recommended Operating Conditions

Symbol	Description	Min	Max	Units
V_{CCINT}	Internal supply voltage relative to GND, $T_j = 0^\circ\text{C}$ to $+85^\circ\text{C}$	0.95	1.05	V
	Internal supply voltage relative to GND, $T_j = -40^\circ\text{C}$ to $+100^\circ\text{C}$	0.95	1.05	V
V_{CCAUX}	Auxiliary supply voltage relative to GND, $T_j = 0^\circ\text{C}$ to $+85^\circ\text{C}$	2.375	2.625	V
	Auxiliary supply voltage relative to GND, $T_j = -40^\circ\text{C}$ to $+100^\circ\text{C}$	2.375	2.625	V
$V_{CCO}^{(1)(2)(3)}$	Supply voltage relative to GND, $T_j = 0^\circ\text{C}$ to $+85^\circ\text{C}$	1.14	2.625	V
	Supply voltage relative to GND, $T_j = -40^\circ\text{C}$ to $+100^\circ\text{C}$	1.14	2.625	V
V_{IN}	2.5V supply voltage relative to GND, $T_j = 0^\circ\text{C}$ to $+85^\circ\text{C}$	GND – 0.20	2.625	V
	2.5V supply voltage relative to GND, $T_j = -40^\circ\text{C}$ to $+100^\circ\text{C}$	GND – 0.20	2.625	V
	2.5V and below supply voltage relative to GND, $T_j = 0^\circ\text{C}$ to $+85^\circ\text{C}$	GND – 0.20	$V_{CCO} + 0.2$	V
	2.5V and below supply voltage relative to GND, $T_j = -40^\circ\text{C}$ to $+100^\circ\text{C}$	GND – 0.20	$V_{CCO} + 0.2$	V
$I_{IN}^{(4)}$	Maximum current through any pin in a powered or unpowered bank when forward biasing the clamp diode.	–	10	mA
$V_{BATT}^{(5)}$	Battery voltage relative to GND, $T_j = 0^\circ\text{C}$ to $+85^\circ\text{C}$	1.0	2.5	V
	Battery voltage relative to GND, $T_j = -40^\circ\text{C}$ to $+100^\circ\text{C}$	1.0	2.5	V
$V_{FS}^{(6)}$	External voltage supply for eFUSE programming	2.375	2.625	V

Notes:

1. Configuration data is retained even if V_{CCO} drops to 0V.
2. Includes V_{CCO} of 1.2V, 1.5V, 1.8V, and 2.5V.
3. The configuration supply voltage V_{CC_CONFIG} is also known as V_{CCO_0} .
4. A total of 100 mA per bank should not be exceeded.
5. V_{BATT} is required only when using bitstream encryption. If battery is not used, connect V_{BATT} to either ground or V_{CCAUX} .
6. When not programming eFUSE, connect V_{FS} to GND.
7. All voltages are relative to ground.

Table 11: DC Characteristics Over Recommended Operating Conditions⁽¹⁾⁽²⁾

Symbol	Description	Min	Typ	Max	Units
V_{DRINT}	Data retention V_{CCINT} voltage (below which configuration data might be lost)	0.75	–	–	V
V_{DRI}	Data retention V_{CCAUX} voltage (below which configuration data might be lost)	2.0	–	–	V
I_{REF}	V_{REF} leakage current per pin	–	–	10	μA
I_L	Input or output leakage current per pin (sample-tested)	–	–	10	μA
$C_{IN}^{(3)}$	Die input capacitance at the pad	–	–	8	pF
I_{RPU}	Pad pull-up (when selected) @ $V_{IN} = 0\text{V}$, $V_{CCO} = 2.5\text{V}$	20	–	80	μA
	Pad pull-up (when selected) @ $V_{IN} = 0\text{V}$, $V_{CCO} = 1.8\text{V}$	8	–	40	μA
	Pad pull-up (when selected) @ $V_{IN} = 0\text{V}$, $V_{CCO} = 1.5\text{V}$	5	–	30	μA
	Pad pull-up (when selected) @ $V_{IN} = 0\text{V}$, $V_{CCO} = 1.2\text{V}$	1	–	20	μA
I_{RPD}	Pad pull-down (when selected) @ $V_{IN} = 2.5\text{V}$	3	–	80	μA
I_{BATT}	Battery supply current	–	–	150	nA
n	Temperature diode ideality factor	–	1.0002	–	n
r	Series resistance	–	5	–	Ω

Notes:

1. Typical values are specified at nominal voltage, 25°C .
2. Maximum value specified for worst case process at 25°C .
3. This measurement represents the die capacitance at the pad, not including the package.

LVPECL DC Specifications (LVPECL_25)

These values are valid when driving a 100Ω differential load only, i.e., a 100Ω resistor between the two receiver pins. The V_{OH} levels are 200 mV below standard LVPECL levels and are compatible with devices tolerant of lower common-mode ranges. Table 19 summarizes the DC output specifications of LVPECL. For more information on using LVPECL, see the *Virtex-6 FPGA SelectIO Resources User Guide*.

Table 19: LVPECL DC Specifications

Symbol	DC Parameter	Min	Typ	Max	Units
V_{OH}	Output High Voltage	$V_{CC} - 1.025$	1.545	$V_{CC} - 0.88$	V
V_{OL}	Output Low Voltage	$V_{CC} - 1.81$	0.795	$V_{CC} - 1.62$	V
V_{ICM}	Input Common-Mode Voltage	0.6	—	2.2	V
V_{IDIFF}	Differential Input Voltage ⁽¹⁾⁽²⁾	0.100	—	1.5	V

Notes:

1. Recommended input maximum voltage not to exceed $V_{CCAUX} + 0.2V$.
2. Recommended input minimum voltage not to go below $-0.5V$.

eFUSE Read Endurance

Table 20 lists the maximum number of read cycle operations expected. For more information, see the *Virtex-6 FPGA Configuration User Guide*.

Table 20: eFUSE Read Endurance

Symbol	Description	Speed Grade				Units
		-3	-2	-1	-1L	
DNA_CYCLES	Number of DNA_PORT READ operations or JTAG ISC_DNA read command operations. Unaffected by SHIFT operations.	30,000,000				Read Cycles
AES_CYCLES	Number of JTAG FUSE_KEY or FUSE_CNTL read command operations. Unaffected by SHIFT operations.	30,000,000				Read Cycles

GTX Transceiver Specifications

GTX Transceiver DC Characteristics

Table 21: Absolute Maximum Ratings for GTX Transceivers⁽¹⁾

Symbol	Description	Min	Max	Units
MGTA VCC	Analog supply voltage for the GTX transmitter and receiver circuits relative to GND	-0.5	1.1	V
MGTA VTT	Analog supply voltage for the GTX transmitter and receiver termination circuits relative to GND	-0.5	1.32	V
MGTA VTTRCAL	Analog supply voltage for the resistor calibration circuit of the GTX transceiver column	-0.5	1.32	V
V_{IN}	Receiver (RXP/RXN) and Transmitter (TXP/TXN) absolute input voltage	-0.5	1.32	V
$V_{MGTRFCLK}$	Reference clock absolute input voltage	-0.5	1.32	V

Notes:

1. Stresses beyond those listed under Absolute Maximum Ratings might cause permanent damage to the device. These are stress ratings only, and functional operation of the device at these or any other conditions beyond those listed under Operating Conditions is not implied. Exposure to Absolute Maximum Ratings conditions for extended periods of time might affect device reliability.

Table 26 summarizes the DC specifications of the clock input of the GTX transceiver. Consult the *Virtex-6 FPGA GTX Transceivers User Guide* for further details.

Table 26: GTX Transceiver Clock DC Input Level Specification

Symbol	DC Parameter	Conditions	Min	Typ	Max	Units
V_{IDIFF}	Differential peak-to-peak input voltage		210	800	2000	mV
R_{IN}	Differential input resistance		90	100	130	Ω
C_{EXT}	Required external AC coupling capacitor		–	100	–	nF

GTX Transceiver Switching Characteristics

Consult *Virtex-6 FPGA GTX Transceivers User Guide* for further information.

Table 27: GTX Transceiver Performance

Symbol	Description	Speed Grade		Units
		-2	-1	
F_{GTXMAX}	Maximum GTX transceiver data rate	3.75	3.75	Gb/s
$F_{GPLLMAX}$	Maximum PLL frequency	2.5	2.5	GHz
$F_{GPLLMIN}$	Minimum PLL frequency	1.2	1.2	GHz

Table 28: GTX Transceiver Dynamic Reconfiguration Port (DRP) Switching Characteristics

Symbol	Description	Speed Grade		Units
		-2	-1	
$F_{GTXDRPCLK}$	GTXDRPCLK maximum frequency	100	100	MHz

Table 29: GTX Transceiver Reference Clock Switching Characteristics

Symbol	Description	Conditions	All Speed Grades			Units
			Min	Typ	Max	
F_{GCLK}	Reference clock frequency range		67.5	–	375	MHz
T_{RCLK}	Reference clock rise time	20% – 80%	–	200	–	ps
T_{FCLK}	Reference clock fall time	80% – 20%	–	200	–	ps
T_{DCREF}	Reference clock duty cycle	Transceiver PLL only	45	50	55	%
T_{LOCK}	Clock recovery frequency acquisition time	Initial PLL lock	–	–	1	ms
T_{PHASE}	Clock recovery phase acquisition time	Lock to data after PLL has locked to the reference clock	–	–	200	μ s

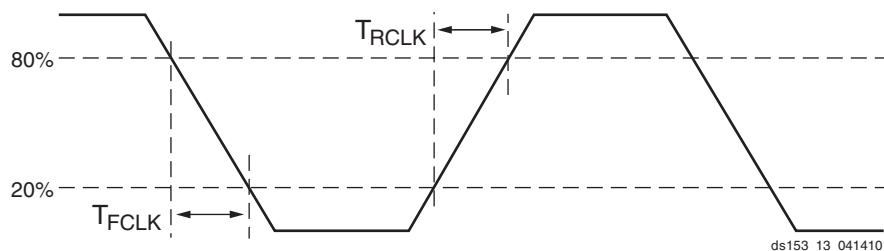


Figure 13: Reference Clock Timing Parameters

Table 30: GTX Transceiver User Clock Switching Characteristics⁽¹⁾

Symbol	Description	Conditions	Speed Grade		Units
			-2	-1	
F _{TXOUT}	TXOUTCLK maximum frequency	Internal 20-bit data path	187.5	187.5	MHz
		Internal 16-bit data path	234.38	234.38	MHz
F _{RXREC}	RXRECCLK maximum frequency	Internal 20-bit data path	187.5	187.5	MHz
		Internal 16-bit data path	234.38	234.38	MHz
T _{RX}	RXUSRCLK maximum frequency		234.38	234.38	MHz
T _{RX2}	RXUSRCLK2 maximum frequency	1 byte interface	376	312.5	MHz
		2 byte interface	234.38	234.38	MHz
		4 byte interface	117.19	117.19	MHz
T _{TX}	TXUSRCLK maximum frequency		234.38	234.38	MHz
T _{TX2}	TXUSRCLK2 maximum frequency	1 byte interface	376	312.5	MHz
		2 byte interface	234.38	234.38	MHz
		4 byte interface	117.19	117.19	MHz

Notes:

1. Clocking must be implemented as described in *Virtex-6 FPGA GTX Transceivers User Guide*.

Table 31: GTX Transceiver Transmitter Switching Characteristics

Symbol	Description	Condition	Min	Typ	Max	Units
F _{GTXTX}	Serial data rate range		0.480	—	F _{GTXMAX}	Gb/s
T _{RTX}	TX Rise time	20%–80%	—	120	—	ps
T _{FTX}	TX Fall time	80%–20%	—	120	—	ps
T _{LLSKEW}	TX lane-to-lane skew ⁽¹⁾		—	—	350	ps
V _{TXOOBVDPP}	Electrical idle amplitude		—	—	15	mV
T _{TXOOBTRANSITION}	Electrical idle transition time		—	—	75	ns
T _{J3.75}	Total Jitter ⁽²⁾⁽³⁾	3.75 Gb/s	—	—	0.34	UI
D _{J3.75}	Deterministic Jitter ⁽²⁾⁽³⁾		—	—	0.16	UI
T _{J3.125}	Total Jitter ⁽²⁾⁽³⁾	3.125 Gb/s	—	—	0.2	UI
D _{J3.125}	Deterministic Jitter ⁽²⁾⁽³⁾		—	—	0.1	UI
T _{J3.125L}	Total Jitter ⁽²⁾⁽³⁾	3.125 Gb/s ⁽⁴⁾	—	—	0.35	UI
D _{J3.125L}	Deterministic Jitter ⁽²⁾⁽³⁾		—	—	0.16	UI
T _{J2.5}	Total Jitter ⁽²⁾⁽³⁾	2.5 Gb/s ⁽⁵⁾	—	—	0.20	UI
D _{J2.5}	Deterministic Jitter ⁽²⁾⁽³⁾		—	—	0.08	UI
T _{J1.25}	Total Jitter ⁽²⁾⁽³⁾	1.25 Gb/s ⁽⁶⁾	—	—	0.15	UI
D _{J1.25}	Deterministic Jitter ⁽²⁾⁽³⁾		—	—	0.06	UI
T _{J600}	Total Jitter ⁽²⁾⁽³⁾	600 Mb/s	—	—	0.1	UI
D _{J600}	Deterministic Jitter ⁽²⁾⁽³⁾		—	—	0.03	UI

IOB Pad Input/Output/3-State Switching Characteristics

Table 38 summarizes the values of standard-specific data input delay adjustments, output delays terminating at pads (based on standard) and 3-state delays.

T_{IOPI} is described as the delay from IOB pad through the input buffer to the I-pin of an IOB pad. The delay varies depending on the capability of the SelectIO input buffer.

T_{IOOP} is described as the delay from the O pin to the IOB pad through the output buffer of an IOB pad. The delay varies depending on the capability of the SelectIO output buffer.

T_{IOTP} is described as the delay from the T pin to the IOB pad through the output buffer of an IOB pad, when 3-state is disabled. The delay varies depending on the SelectIO capability of the output buffer.

Table 39 summarizes the value of T_{IOTPHZ} . T_{IOTPHZ} is described as the delay from the T pin to the IOB pad through the output buffer of an IOB pad, when 3-state is enabled (i.e., a high impedance state).

Table 38: IOB Switching Characteristics

I/O Standard	T _{IOPI}		T _{IOOP}		T _{IOTP}		Units
	Speed Grade		Speed Grade		Speed Grade		
	-2	-1	-2	-1	-2	-1	
LVDS_25	1.09	1.09	1.68	1.68	1.68	1.68	ns
LVDSEXT_25	1.09	1.09	1.84	1.84	1.84	1.84	ns
HT_25	1.09	1.09	1.78	1.78	1.78	1.78	ns
BLVDS_25	1.09	1.09	1.67	1.67	1.67	1.67	ns
RSDS_25 (point to point)	1.09	1.09	1.68	1.68	1.68	1.68	ns
HSTL_I	1.06	1.06	1.73	1.73	1.73	1.73	ns
HSTL_II	1.06	1.06	1.74	1.74	1.74	1.74	ns
HSTL_III	1.06	1.06	1.71	1.71	1.71	1.71	ns
HSTL_I_18	1.06	1.06	1.75	1.75	1.75	1.75	ns
HSTL_II_18	1.06	1.06	1.81	1.81	1.81	1.81	ns
HSTL_III_18	1.06	1.06	1.71	1.71	1.71	1.71	ns
SSTL2_I	1.06	1.06	1.77	1.77	1.77	1.77	ns
SSTL2_II	1.06	1.06	1.72	1.72	1.72	1.72	ns
SSTL15	1.06	1.06	1.71	1.71	1.71	1.71	ns
LVC MOS25, Slow, 2 mA	0.66	0.66	6.01	6.01	6.01	6.01	ns
LVC MOS25, Slow, 4 mA	0.66	0.66	3.79	3.79	3.79	3.79	ns
LVC MOS25, Slow, 6 mA	0.66	0.66	3.08	3.08	3.08	3.08	ns
LVC MOS25, Slow, 8 mA	0.66	0.66	2.72	2.72	2.72	2.72	ns
LVC MOS25, Slow, 12 mA	0.66	0.66	2.17	2.17	2.17	2.17	ns
LVC MOS25, Slow, 16 mA	0.66	0.66	2.29	2.29	2.29	2.29	ns
LVC MOS25, Slow, 24 mA	0.66	0.66	2.02	2.02	2.02	2.02	ns
LVC MOS25, Fast, 2 mA	0.66	0.66	6.04	6.04	6.04	6.04	ns
LVC MOS25, Fast, 4 mA	0.66	0.66	3.82	3.82	3.82	3.82	ns
LVC MOS25, Fast, 6 mA	0.66	0.66	2.99	2.99	2.99	2.99	ns
LVC MOS25, Fast, 8 mA	0.66	0.66	2.65	2.65	2.65	2.65	ns
LVC MOS25, Fast, 12 mA	0.66	0.66	2.08	2.08	2.08	2.08	ns
LVC MOS25, Fast, 16 mA	0.66	0.66	2.13	2.13	2.13	2.13	ns
LVC MOS25, Fast, 24 mA	0.66	0.66	1.99	1.99	1.99	1.99	ns

Table 43: OLOGIC Switching Characteristics

Symbol	Description	Speed Grade		Units
		-2	-1	
Setup/Hold				
T _{ODCK} /T _{OCKD}	D1/D2 pins Setup/Hold with respect to CLK	0.54/−0.11	0.54/−0.11	ns
T _{OOCECK} /T _{OCKOCE}	OCE pin Setup/Hold with respect to CLK	0.22/−0.05	0.22/−0.05	ns
T _{OSRCK} /T _{OCKSR}	SR pin Setup/Hold with respect to CLK	0.71/−0.29	0.71/−0.29	ns
T _{OTCK} /T _{OCKT}	T1/T2 pins Setup/Hold with respect to CLK	0.56/−0.10	0.56/−0.10	ns
T _{OTCECK} /T _{OCKTCE}	TCE pin Setup/Hold with respect to CLK	0.21/−0.05	0.21/−0.05	ns
Combinatorial				
T _{DOQ}	D1 to OQ out or T1 to TQ out	1.01	1.01	ns
Sequential Delays				
T _{OCKQ}	CLK to OQ/TQ out	0.71	0.71	ns
T _{RQ}	SR pin to OQ/TQ out	1.05	1.05	ns
T _{GSRQ}	Global Set/Reset to Q outputs	10.51	10.51	ns
Set/Reset				
T _{RPW}	Minimum Pulse Width, SR inputs	1.20	1.20	ns, Min

Input Serializer/Deserializer Switching Characteristics

Table 44: ISERDES Switching Characteristics

Symbol	Description	Speed Grade		Units
		-2	-1	
Setup/Hold for Control Lines				
T _{ISCKK_BITS} SLIP/ T _{ISCKC_BITS} SLIP	BITS _{SLIP} pin Setup/Hold with respect to CLKDIV	0.09/0.17	0.09/0.17	ns
T _{ISCKK_CE} / T _{ISCKC_CE} ⁽²⁾	CE pin Setup/Hold with respect to CLK (for CE1)	0.27/0.04	0.27/0.04	ns
T _{ISCKK_CE2} / T _{ISCKC_CE2} ⁽²⁾	CE pin Setup/Hold with respect to CLKDIV (for CE2)	–0.06/0.31	–0.06/0.31	ns
Setup/Hold for Data Lines				
T _{ISDCK_D} /T _{ISCKD_D}	D pin Setup/Hold with respect to CLK	0.09/0.11	0.09/0.11	ns
T _{ISDCK_DDLY} /T _{ISCKD_DDLY}	DDLY pin Setup/Hold with respect to CLK (using IODELAY) ⁽¹⁾	0.14/0.07	0.14/0.07	ns
T _{ISDCK_D_DDR} /T _{ISCKD_D_DDR}	D pin Setup/Hold with respect to CLK at DDR mode	0.09/0.11	0.09/0.11	ns
T _{ISDCK_DDLY_DDR} /T _{ISCKD_DDLY_DDR}	D pin Setup/Hold with respect to CLK at DDR mode (using IODELAY) ⁽¹⁾	0.14/0.07	0.14/0.07	ns
Sequential Delays				
T _{ISCKO_Q}	CLKDIV to out at Q pin	0.75	0.75	ns
Propagation Delays				
T _{ISDO_DO}	D input to DO output pin	0.25	0.25	ns

Notes:

- Recorded at 0 tap value.
- T_{ISCK_CE2} and T_{ISCKC_CE2} are reported as T_{ISCK_CE}/T_{ISCKC_CE} in a TRACE report.

Table 47: CLB Switching Characteristics (Cont'd)

Symbol	Description	Speed Grade		Units
		-2	-1	
T_{BxB}	BX inputs to BMUX output	0.39	0.45	ns, Max
T_{BXD}	BX inputs to DMUX output	0.50	0.58	ns, Max
T_{CXB}	CX inputs to CMUX output	0.34	0.38	ns, Max
T_{CXD}	CX inputs to DMUX output	0.40	0.45	ns, Max
T_{DXD}	DX inputs to DMUX output	0.38	0.44	ns, Max
T_{OPCYA}	An input to COUT output	0.42	0.47	ns, Max
T_{OPCYB}	Bn input to COUT output	0.42	0.47	ns, Max
T_{OPCYC}	Cn input to COUT output	0.35	0.39	ns, Max
T_{OPCYD}	Dn input to COUT output	0.33	0.37	ns, Max
T_{AXCY}	AX input to COUT output	0.33	0.38	ns, Max
T_{BXCy}	BX input to COUT output	0.28	0.32	ns, Max
T_{CXCy}	CX input to COUT output	0.20	0.23	ns, Max
T_{DXCY}	DX input to COUT output	0.19	0.22	ns, Max
T_{BYP}	CIN input to COUT output	0.08	0.09	ns, Max
T_{CINA}	CIN input to AMUX output	0.28	0.32	ns, Max
T_{CINB}	CIN input to BMUX output	0.29	0.34	ns, Max
T_{CINC}	CIN input to CMUX output	0.30	0.34	ns, Max
T_{CIND}	CIN input to DMUX output	0.33	0.38	ns, Max
Sequential Delays				
T_{CKO}	Clock to AQ – DQ outputs	0.39	0.44	ns, Max
T_{SHCKO}	Clock to AMUX – DMUX outputs	0.47	0.54	ns, Max
Setup and Hold Times of CLB Flip-Flops Before/After Clock CLK				
T_{DICK}/T_{CKDI}	A – D input to CLK on A – D Flip Flops	0.43/0.20	0.50/0.23	ns, Min
$T_{CECK_CLB}/T_{CKCE_CLB}$	CE input to CLK on A – D Flip Flops	0.32/–0.01	0.37/–0.01	ns, Min
T_{SRCK}/T_{CKSR}	SR input to CLK on A – D Flip Flops	0.52/–0.08	0.60/–0.08	ns, Min
T_{CINCK}/T_{CKCIN}	CIN input to CLK on A – D Flip Flops	0.24/0.17	0.27/0.19	ns, Min
Set/Reset				
T_{SRMIN}	SR input minimum pulse width	0.97	0.97	ns, Min
T_{RQ}	Delay from SR input to AQ – DQ flip-flops	0.68	0.78	ns, Max
T_{CEO}	Delay from CE input to AQ – DQ flip-flops	0.59	0.67	ns, Max
F_{TOG}	Toggle frequency (for export control)	1098.00	1098.00	MHz

Notes:

1. A Zero “0” Hold Time listing indicates no hold time or a negative hold time. Negative values can not be guaranteed “best-case”, but if a “0” is listed, there is no positive hold time.
2. These items are of interest for Carry Chain applications.

Block RAM and FIFO Switching Characteristics

Table 50: Block RAM and FIFO Switching Characteristics

Symbol	Description	Speed Grade		Units
		-2	-1	
Block RAM and FIFO Clock-to-Out Delays				
T _{RCKO_DO} and T _{RCKO_DO_REG} ⁽¹⁾	Clock CLK to DOUT output (without output register) ⁽²⁾⁽³⁾	2.08	2.39	ns, Max
	Clock CLK to DOUT output (with output register) ⁽⁴⁾⁽⁵⁾	0.75	0.86	ns, Max
T _{RCKO_DO_ECC} and T _{RCKO_DO_ECC_REG}	Clock CLK to DOUT output with ECC (without output register) ⁽²⁾⁽³⁾	3.30	3.79	ns, Max
	Clock CLK to DOUT output with ECC (with output register) ⁽⁴⁾⁽⁵⁾	0.86	0.98	ns, Max
T _{RCKO_CASC} and T _{RCKO_CASC_REG}	Clock CLK to DOUT output with Cascade (without output register) ⁽²⁾	3.18	3.65	ns, Max
	Clock CLK to DOUT output with Cascade (with output register) ⁽⁴⁾	1.58	1.81	ns, Max
T _{RCKO_FLAGS}	Clock CLK to FIFO flags outputs ⁽⁶⁾	0.91	1.05	ns, Max
T _{RCKO_POINTERS}	Clock CLK to FIFO pointers outputs ⁽⁷⁾	1.09	1.25	ns, Max
T _{RCKO_RDCOUNT}	Clock CLK to FIFO Read Counter	1.09	1.25	ns, Max
T _{RCKO_WRCOUNT}	Clock CLK to FIFO Write Counter	1.09	1.25	ns, Max
T _{RCKO_SDBIT_ECC} and T _{RCKO_SDBIT_ECC_REG}	Clock CLK to BITERR (with output register)	0.76	0.87	ns, Max
	Clock CLK to BITERR (without output register)	2.84	3.26	ns, Max
T _{RCKO_PARITY_ECC}	Clock CLK to ECCPARITY in ECC encode only mode	1.06	1.21	ns, Max
T _{RCKO_RDADDR_ECC} and T _{RCKO_RDADDR_ECC_REG}	Clock CLK to RDADDR output with ECC (without output register)	0.90	1.03	ns, Max
	Clock CLK to RDADDR output with ECC (with output register)	0.92	1.06	ns, Max
Setup and Hold Times Before/After Clock CLK				
T _{RCCK_ADDR} /T _{RCKC_ADDR}	ADDR inputs ⁽⁸⁾	0.62/0.32	0.72/0.37	ns, Min
T _{RDCK_DI} /T _{RCKD_DI}	DIN inputs ⁽⁹⁾	1.11/0.34	1.28/0.39	ns, Min
T _{RDCK_DI_ECC} /T _{RCKD_DI_ECC}	DIN inputs with block RAM ECC in standard mode ⁽⁹⁾	0.59/0.34	0.68/0.39	ns, Min
	DIN inputs with block RAM ECC encode only ⁽⁹⁾	0.85/0.34	0.97/0.39	ns, Min
	DIN inputs with FIFO ECC in standard mode ⁽⁹⁾	1.02/0.34	1.17/0.39	ns, Min
T _{RCCK_CLK} /T _{RCKC_CLK}	Inject single/double bit error in ECC mode	1.20/0.29	1.38/0.33	ns, Min
T _{RCCK_RDEN} /T _{RCKC_RDEN}	Block RAM Enable (EN) input	0.41/0.30	0.47/0.34	ns, Min
T _{RCCK_REGCE} /T _{RCKC_REGCE}	CE input of output register	0.22/0.31	0.25/0.35	ns, Min
T _{RCCK_RSTREG} /T _{RCKC_RSTREG}	Synchronous RSTREG input	0.28/0.26	0.32/0.29	ns, Min
T _{RCCK_RSTRAM} /T _{RCKC_RSTRAM}	Synchronous RSTRAM input	0.41/0.27	0.47/0.31	ns, Min
T _{RCCK_WE} /T _{RCKC_WE}	Write Enable (WE) input (block RAM only)	0.52/0.35	0.60/0.40	ns, Min
T _{RCCK_WREN} /T _{RCKC_WREN}	WREN FIFO inputs	0.55/0.30	0.64/0.34	ns, Min
T _{RCCK_RDEN} /T _{RCKC_RDEN}	RDEN FIFO inputs	0.55/0.30	0.63/0.34	ns, Min
Reset Delays				
T _{RCO_FLAGS}	Reset RST to FIFO Flags/Pointers ⁽¹⁰⁾	1.10	1.27	ns, Max
T _{RCCK_RSTREG} /T _{RCKC_RSTREG}	FIFO reset timing ⁽¹¹⁾	0.28/0.26	0.32/0.29	ns, Min

DSP48E1 Switching Characteristics

Table 51: DSP48E1 Switching Characteristics

Symbol	Description	Speed Grade		Units
		-2	-1	
Setup and Hold Times of Data/Control Pins to the Input Register Clock				
$T_{DSPDCK_A, ACIN; B, BCIN}_{AREG; BREG}/T_{DSPCKD_A, ACIN; B, BCIN}_{AREG; BREG}$	{A, ACIN, B, BCIN} input to {A, B} register CLK	0.35/0.34	0.41/0.39	ns
$T_{DSPDCK_C_CREG}/T_{DSPCKD_C_CREG}$	C input to C register CLK	0.22/0.24	0.26/0.27	ns
$T_{DSPDCK_D_DREG}/T_{DSPCKD_D_DREG}$	D input to D register CLK	0.15/0.39	0.17/0.44	ns
Setup and Hold Times of Data Pins to the Pipeline Register Clock				
$T_{DSPDCK_A, ACIN, B, BCIN}_{PREG_MULT}/T_{DSPCKD_A, ACIN, B, BCIN}_{PREG_MULT}$	{A, ACIN, B, BCIN} input to M register CLK	3.21/0.02	3.69/0.02	ns
$T_{DSPDCK_A, D}_{ADREG}/T_{DSPCKD_A, D}_{ADREG}$	{A, D} input to AD register CLK	1.69/0.13	1.94/0.15	ns
Setup and Hold Times of Data/Control Pins to the Output Register Clock				
$T_{DSPDCK_A, ACIN, B, BCIN}_{PREG_MULT}/T_{DSPCKD_A, ACIN, B, BCIN}_{PREG_MULT}$	{A, ACIN, B, BCIN} input to P register CLK using multiplier	5.20/−0.19	5.97/−0.22	ns
$T_{DSPDCK_D_DREG_MULT}/T_{DSPCKD_D_DREG_MULT}$	D input to P register CLK	4.90/−0.65	5.63/−0.75	ns
$T_{DSPDCK_A, ACIN, B, BCIN}_{PREG}/T_{DSPCKD_A, ACIN, B, BCIN}_{PREG}$	{A, ACIN, B, BCIN} input to P register CLK not using multiplier	2.15/−0.19	2.47/−0.22	ns
$T_{DSPDCK_C_PREG}/T_{DSPCKD_C_PREG}$	C input to P register CLK	1.91/−0.14	2.19/−0.17	ns
$T_{DSPDCK_PCIN, CARRYCASCIN, MULTSIGNIN}_{PREG}/T_{DSPCKD_PCIN, CARRYCASCIN, MULTSIGNIN}_{PREG}$	{PCIN, CARRYCASCIN, MULTSIGNIN} input to P register CLK	1.67/−0.04	1.92/−0.05	ns
Setup and Hold Times of the CE Pins				
$T_{DSPDCK_CEA; CEB}_{AREG; BREG}/T_{DSPCKD_CEA; CEB}_{AREG; BREG}$	{CEA, CEB} input to {A; B} register CLK	0.22/0.25	0.25/0.29	ns
$T_{DSPDCK_CEC_CREG}/T_{DSPCKD_CEC_CREG}$	CEC input to C register CLK	0.24/0.23	0.28/0.27	ns
$T_{DSPDCK_CED_DREG}/T_{DSPCKD_CED_DREG}$	CED input to D register CLK	0.31/0.14	0.35/0.16	ns
$T_{DSPDCK_CEM_MREG}/T_{DSPCKD_CEM_MREG}$	CEM input to M register CLK	0.26/0.25	0.30/0.28	ns
$T_{DSPDCK_CEP_PREG}/T_{DSPCKD_CEP_PREG}$	CEP input to P register CLK	0.46/0.03	0.53/0.03	ns
Setup and Hold Times of the RST Pins				
$T_{DSPDCK_RSTA; RSTB}_{AREG; BREG}/T_{DSPCKD_RSTA; RSTB}_{AREG; BREG}$	{RSTA, RSTB} input to {A, B} register CLK	0.38/0.22	0.43/0.25	ns
$T_{DSPDCK_RSTC_CREG}/T_{DSPCKD_RSTC_CREG}$	RSTC input to C register CLK	0.23/0.09	0.27/0.11	ns
$T_{DSPDCK_RSTD_DREG}/T_{DSPCKD_RSTD_DREG}$	RSTD input to D register CLK	0.38/0.19	0.44/0.21	ns
$T_{DSPDCK_RSTM_MREG}/T_{DSPCKD_RSTM_MREG}$	RSTM input to M register CLK	0.26/0.30	0.30/0.35	ns
$T_{DSPDCK_RSTP_PREG}/T_{DSPCKD_RSTP_PREG}$	RSTP input to P register CLK	0.33/0.05	0.41/0.06	ns
Combinatorial Delays from Input Pins to Output Pins				
$T_{DSPDO_A, B}_{P, CARRYOUT_MULT}$	{A, B} input to {P, CARRYOUT} output using multiplier	5.08	5.84	ns
$T_{DSPDO_D}_{P, CARRYOUT_MULT}$	D input to {P, CARRYOUT} output using multiplier	4.82	5.54	ns
$T_{DSPDO_A, B}_{P, CARRYOUT}$	{A, B} input to {P, CARRYOUT} output not using multiplier	2.07	2.38	ns
$T_{DSPDO_C, CARRYIN}_{P, CARRYOUT}$	{C, CARRYIN} input to {P, CARRYOUT} output	1.83	2.10	ns

Table 51: DSP48E1 Switching Characteristics (Cont'd)

Symbol	Description	Speed Grade		Units
		-2	-1	
Combinatorial Delays from Input Pins to Cascading Output Pins				
T _{DSPDO_{A; B}_{ACOUT; BCOUT}}	{A, B} input to {ACOUT, BCOUT} output	0.65	0.75	ns
T _{DSPDO_{A, B}_{PCOUT, CARRYCASCOUT, MULTSIGNOUT}_MULT}	{A, B} input to {PCOUT, CARRYCASCOUT, MULTSIGNOUT} output using multiplier	5.24	6.03	ns
T _{DSPDO_D_{PCOUT, CARRYCASCOUT, MULTSIGNOUT}_MULT}	D input to {PCOUT, CARRYCASCOUT, MULTSIGNOUT} output using multiplier	4.94	5.68	ns
T _{DSPDO_{A, B}_{PCOUT, CARRYCASCOUT, MULTSIGNOUT}}	{A, B} input to {PCOUT, CARRYCASCOUT, MULTSIGNOUT} output not using multiplier	2.19	2.52	ns
T _{DSPDO_{C, CARRYIN}_{PCOUT, CARRYCASCOUT, MULTSIGNOUT}}	{C, CARRYIN} input to {PCOUT, CARRYCASCOUT, MULTSIGNOUT} output	1.95	2.25	ns
Combinatorial Delays from Cascading Input Pins to All Output Pins				
T _{DSPDO_{ACIN, BCIN}_{P, CARRYOUT}_MULT}	{ACIN, BCIN} input to {P, CARRYOUT} output using multiplier	4.97	5.72	ns
T _{DSPDO_{ACIN, BCIN}_{P, CARRYOUT}}	{ACIN, BCIN} input to {P, CARRYOUT} output not using multiplier	1.92	2.21	ns
T _{DSPDO_{ACIN; BCIN}_{ACOUT; BCOUT}}	{ACIN, BCIN} input to {ACOUT, BCOUT} output	0.49	0.57	ns
T _{DSPDO_{ACIN, BCIN}_{PCOUT, CARRYCASCOUT, MULTSIGNOUT}_MULT}	{ACIN, BCIN} input to {PCOUT, CARRYCASCOUT, MULTSIGNOUT} output using multiplier	5.10	5.86	ns
T _{DSPDO_{ACIN, BCIN}_{PCOUT, CARRYCASCOUT, MULTSIGNOUT}}	{ACIN, BCIN} input to {PCOUT, CARRYCASCOUT, MULTSIGNOUT} output not using multiplier	2.05	2.35	ns
T _{DSPDO_{PCIN, CARRYCASCIN, MULTSIGNIN}_{P, CARRYOUT}}	{PCIN, CARRYCASCIN, MULTSIGNIN} input to {P, CARRYOUT} output	1.60	1.83	ns
T _{DSPDO_{PCIN, CARRYCASCIN, MULTSIGNIN}_{PCOUT, CARRYCASCOUT, MULTSIGNOUT}}	{PCIN, CARRYCASCIN, MULTSIGNIN} input to {PCOUT, CARRYCASCOUT, MULTSIGNOUT} output	1.72	1.98	ns
Clock to Outs from Output Register Clock to Output Pins				
T _{DSPCKO_{P, CARRYOUT}_PREG}	CLK (PREG) to {P, CARRYOUT} output	0.50	0.57	ns
T _{DSPCKO_{PCOUT, CARRYCASCOUT, MULTSIGNOUT}_PREG}	CLK (PREG) to {CARRYCASCOUT, PCOUT, MULTSIGNOUT} output	0.50	0.66	ns
Clock to Outs from Pipeline Register Clock to Output Pins				
T _{DSPCKO_{P, CARRYOUT}_MREG}	CLK (MREG) to {P, CARRYOUT} output	2.30	2.65	ns
T _{DSPCKO_{PCOUT, CARRYCASCOUT, MULTSIGNOUT}_MREG}	CLK (MREG) to {PCOUT, CARRYCASCOUT, MULTSIGNOUT} output	2.43	2.79	ns
T _{DSPCKO_{P, CARRYOUT}_ADREG_MULT}	CLK (ADREG) to {P, CARRYOUT} output	3.72	4.72	ns
T _{DSPCKO_{PCOUT, CARRYCASCOUT, MULTSIGNOUT}_ADREG_MULT}	CLK (ADREG) to {PCOUT, CARRYCASCOUT, MULTSIGNOUT} output	3.84	4.42	ns
Clock to Outs from Input Register Clock to Output Pins				
T _{DSPCKO_{P, CARRYOUT}_{AREG, BREG}_MULT}	CLK (AREG, BREG) to {P, CARRYOUT} output using multiplier	5.36	6.16	ns
T _{DSPCKO_{P, CARRYOUT}_{AREG, BREG}}	CLK (AREG, BREG) to {P, CARRYOUT} output not using multiplier	2.27	2.61	ns
T _{DSPCKO_{P, CARRYOUT}_CREG}	CLK (CREG) to {P, CARRYOUT} output	2.27	2.61	ns
T _{DSPCKO_{P, CARRYOUT}_DREG_MULT}	CLK (DREG) to {P, CARRYOUT} output	5.25	6.04	ns

Configuration Switching Characteristics

Table 52: Configuration Switching Characteristics

Symbol	Description	Speed Grade		Units
		-2	-1	
Power-up Timing Characteristics				
T _{PL} ⁽¹⁾	Program Latency	3	3	ms, Max
T _{POR} ⁽¹⁾	Power-on-Reset	15/55	15/55	ms, Min/Max
T _{ICCK}	CCLK (output) delay	400	400	ns, Min
T _{PROGRAM}	Program Pulse Width	250	250	ns, Min
Master/Slave Serial Mode Programming Switching ⁽¹⁾				
T _{DCCK} /T _{CCKD}	DIN Setup/Hold, slave mode	4.0/0.0	4.0/0.0	ns, Min
T _{DSCCK} /T _{SCCKD}	DIN Setup/Hold, master mode	4.0/0.0	4.0/0.0	ns, Min
T _{CCO}	DOOUT at 2.5V	6	6	ns, Max
	DOOUT at 1.8V	6	6	ns, Max
F _{MCCK}	Maximum CCLK frequency, serial modes	100	100	MHz, Max
F _{MCCKTOL}	Frequency Tolerance, master mode with respect to nominal CCLK	55	55	%
F _{MSCCK}	Slave mode external CCLK	100	100	MHz
SelectMAP Mode Programming Switching				
T _{SMDCCK} /T _{SMCCKD}	SelectMAP Data Setup/Hold	4.0/0.0	4.0/0.0	ns, Min
T _{SMCSCCK} /T _{SMCCKCS}	CSI_B Setup/Hold	4.0/0.0	4.0/0.0	ns, Min
T _{SMCCKW} /T _{SMWCKK}	RDWR_B Setup/Hold	10.0/0.0	10.0/0.0	ns, Min
T _{SMCKCSO}	CSO_B clock to out (330 Ω pull-up resistor required)	7	7	ns, Min
T _{SMCO}	CCLK to DATA out in readback at 2.5V	8	8	ns, Max
	CCLK to DATA out in readback at 1.8V	8	8	ns, Max
T _{SMCKBY}	CCLK to BUSY out in readback at 2.5V	6	6	ns, Max
	CCLK to BUSY out in readback at 1.8V	6	6	ns, Max
F _{SMCCK}	Maximum Frequency with respect to nominal CCLK	100	100	MHz, Max
F _{RBCKK}	Maximum Readback Frequency with respect to nominal CCLK	100	100	MHz, Max
F _{MCCKTOL}	Frequency Tolerance with respect to nominal CCLK	55	55	%
Boundary-Scan Port Timing Specifications				
T _{TAPTCK} /T _{TCKTAP}	TMS and TDI Setup time before TCK/ Hold time after TCK	3.0/2.0	3.0/2.0	ns, Min
T _{TCKTDO}	TCK falling edge to TDO output valid at 2.5V	6	6	ns, Max
	TCK falling edge to TDO output valid at 1.8V	6	6	ns, Max
F _{TCK}	Maximum configuration TCK clock frequency	66	66	MHz, Max
F _{TCKB_MIN}	Minimum boundary-scan TCK clock frequency when using IEEE Std 1149.6 (AC-JTAG). Minimum operating temperature for IEEE Std 1149.6 is 0°C.	15	15	MHz, Min
F _{TCKB}	Maximum boundary-scan TCK clock frequency	66	66	MHz, Max

Table 55: Regional Clock Switching Characteristics (BUFR)

Symbol	Description	Speed Grade		Units
		-2	-1	
T_{BRCKO_O}	Clock to out delay from I to O	0.75	0.75	ns
		0.75	0.75	ns
		0.75	0.75	ns
		0.75	0.75	ns
$T_{BRCKO_O_BYP}$	Clock to out delay from I to O with Divide Bypass attribute set	0.37	0.37	ns
		0.37	0.37	ns
		0.37	0.37	ns
		0.37	0.37	ns
T_{BRDO_O}	Propagation delay from CLR to O	0.83	0.83	ns
Maximum Frequency				
F_{MAX}	Regional clock tree (BUFR)	300	300	MHz

Table 56: Horizontal Clock Buffer Switching Characteristics (BUFH)

Symbol	Description	Speed Grade		Units
		-2	-1	
T_{BHCKO_O}	BUFH delay from I to O	0.13	0.13	ns
T_{BHCK_CE}/T_{BHCK_CE}	CE pin Setup and Hold	0.05/0.05	0.05/0.05	ns
Maximum Frequency				
F_{MAX}	Horizontal clock buffer (BUFH)	700	700	MHz

MMCM Switching Characteristics

Table 57: MMCM Specification

Symbol	Description	Speed Grade		Units
		-2	-1	
F_{INMAX}	Maximum Input Clock Frequency ⁽¹⁾	700	700	MHz
F_{INMIN}	Minimum Input Clock Frequency	10	10	MHz
$F_{INJITTER}$	Maximum Input Clock Period Jitter	< 20% of clock input period or 1 ns Max		
F_{INDUTY}	Allowable Input Duty Cycle: 10—49 MHz	25/75		%
	Allowable Input Duty Cycle: 50—199 MHz	30/70		%
	Allowable Input Duty Cycle: 200—399 MHz	35/65		%
	Allowable Input Duty Cycle: 400—499 MHz	40/60		%
	Allowable Input Duty Cycle: >500 MHz	45/55		%
F_{MIN_PSCLK}	Minimum Dynamic Phase Shift Clock Frequency	0.01	0.01	MHz
F_{MAX_PSCLK}	Maximum Dynamic Phase Shift Clock Frequency	450	450	MHz
F_{VCOMIN}	Minimum MMCM VCO Frequency	600	600	MHz
F_{VCOMAX}	Maximum MMCM VCO Frequency	1200	1200	MHz
$F_{BANDWIDTH}$	Low MMCM Bandwidth at Typical ⁽²⁾	1.00	1.00	MHz
	High MMCM Bandwidth at Typical ⁽²⁾	4.00	4.00	MHz

Table 57: MMCM Specification (Cont'd)

Symbol	Description	Speed Grade		Units
		-2	-1	
$T_{\text{STATPHAOFFSET}}$	Static Phase Offset of the MMCM Outputs ⁽³⁾	0.12	0.12	ns
$T_{\text{OUTJITTER}}$	MMCM Output Jitter ⁽⁴⁾	Note 1		
T_{OUTDUTY}	MMCM Output Clock Duty Cycle Precision ⁽⁵⁾	0.20	0.20	ns
T_{LOCKMAX}	MMCM Maximum Lock Time	100	100	μs
F_{OUTMAX}	MMCM Maximum Output Frequency	700	700	MHz
F_{OUTMIN}	MMCM Minimum Output Frequency ⁽⁶⁾⁽⁷⁾	4.69	4.69	MHz
T_{EXTFDVAR}	External Clock Feedback Variation	< 20% of clock input period or 1 ns Max		
RST_{MINPULSE}	Minimum Reset Pulse Width	1.5	1.5	ns
F_{PFDMAX}	Maximum Frequency at the Phase Frequency Detector with Bandwidth Set to High or Optimized ⁽⁸⁾	450	450	MHz
	Maximum Frequency at the Phase Frequency Detector with Bandwidth Set to Low	300	300	MHz
F_{PFDMIN}	Minimum Frequency at the Phase Frequency Detector with Bandwidth Set to High or Optimized	135	135	MHz
	Minimum Frequency at the Phase Frequency Detector with Bandwidth Set to Low	10.00	10.00	MHz
T_{FBDELAY}	Maximum Delay in the Feedback Path	3 ns Max or one CLKIN cycle		
$T_{\text{MMCMCKD_PSEN}} / T_{\text{MMCMCKD_PSEN}}$	Setup and Hold of Phase Shift Enable	1.04/0.00	1.04/0.00	ns
$T_{\text{MMCMCKD_PSINCDEC}} / T_{\text{MMCMCKD_PSINCDEC}}$	Setup and Hold of Phase Shift Increment/Decrement	1.04/0.00	1.04/0.00	ns
$T_{\text{MMCMCKO_PSDONE}}$	Phase Shift Clock-to-Out of PSDONE	0.38	0.38	ns

Notes:

1. When $\text{DIVCLK_DIVIDE} = 3$ or 4 , F_{INMAX} is 315 MHz.
2. The MMCM does not filter typical spread-spectrum input clocks because they are usually far below the bandwidth filter frequencies.
3. The static offset is measured between any MMCM outputs with identical phase.
4. Values for this parameter are available in the Architecture Wizard.
5. Includes global clock buffer.
6. Calculated as $F_{\text{VCO}}/128$ assuming output duty cycle is 50%.
7. When $\text{CASCADE4_OUT} = \text{TRUE}$, F_{OUTMIN} is 0.036 MHz.
8. In ISE software 12.3 (or earlier versions supporting the Virtex-6 family), the phase frequency detector Optimized bandwidth setting is equivalent to the High bandwidth setting. Starting with ISE software 12.4, the Optimized bandwidth setting is automatically adjusted to Low when the software can determine that the phase frequency detector input is less than 135 MHz.

Virtex-6 CXT Device Pin-to-Pin Output Parameter Guidelines

All devices are 100% functionally tested. The representative values for typical pin locations and normal clock loading are listed in Table 58. Values are expressed in nanoseconds unless otherwise noted.

Table 58: Global Clock Input to Output Delay Without MMCM

Symbol	Description	Device	Speed Grade		Units
			-2	-1	
LVCMOS25 Global Clock Input to Output Delay using Output Flip-Flop, 12mA, Fast Slew Rate, <i>without</i> MMCM.					
T _{ICKOF}	Global Clock input and OUTFF <i>without</i> MMCM	XC6VCX75T	5.88	5.88	ns
		XC6VCX130T	6.00	6.00	ns
		XC6VCX195T	6.13	6.13	ns
		XC6VCX240T	6.13	6.13	ns

Notes:

1. Listed above are representative values where one global clock input drives one vertical clock line in each accessible column, and where all accessible IOB and CLB flip-flops are clocked by the global clock net.

Table 59: Global Clock Input to Output Delay With MMCM

Symbol	Description	Device	Speed Grade		Units
			-2	-1	
LVCMOS25 Global Clock Input to Output Delay using Output Flip-Flop, 12mA, Fast Slew Rate, <i>with</i> MMCM.					
T _{ICKOFMMCMGC}	Global Clock Input and OUTFF <i>with</i> MMCM	XC6VCX75T	2.77	2.77	ns
		XC6VCX130T	2.78	2.78	ns
		XC6VCX195T	2.78	2.78	ns
		XC6VCX240T	2.79	2.79	ns

Notes:

1. Listed above are representative values where one global clock input drives one vertical clock line in each accessible column, and where all accessible IOB and CLB flip-flops are clocked by the global clock net.
2. MMCM output jitter is already included in the timing calculation.

Table 60: Clock-Capable Clock Input to Output Delay With MMCM

Symbol	Description	Device	Speed Grade		Units
			-2	-1	
LVCMOS25 Clock-capable Clock Input to Output Delay using Output Flip-Flop, 12mA, Fast Slew Rate, <i>with</i> MMCM.					
T _{ICKOFMMCMCC}	Clock-capable Clock Input and OUTFF <i>with</i> MMCM	XC6VCX75T	2.63	2.63	ns
		XC6VCX130T	2.65	2.65	ns
		XC6VCX195T	2.65	2.65	ns
		XC6VCX240T	2.65	2.65	ns

Notes:

1. Listed above are representative values where one global clock input drives one vertical clock line in each accessible column, and where all accessible IOB and CLB flip-flops are clocked by the global clock net.
2. MMCM output jitter is already included in the timing calculation.

Date	Version	Description of Revisions
06/08/10	1.2	Revised GTX Transceivers in CXT Devices, page 5. Added V_{FS} and revised the V_{IN} and V_{TS} values in Table 9, page 11. Added V_{FS} and note 6 to Table 10. Revised description of C_{IN} in Table 11, including adding note 3. Updated Table 13 including adding note 2. Removed DIFF SSTL15 and added values to SSTL15 in Table 15. Updated Table 16 through Table 19. Added eFUSE Read Endurance section. Updated entire GTX Transceivers in CXT Devices section. Changed specifications of PCI Express in Table 34. In Table 35, removed RLDRAM II and revised and added values to other interface performance specifications. Updated speed specification to v1.04 with appropriate changes to Table 36. Revised the IOB switching characteristics in Table 38. Updated values in Table 39 and note 4 in Table 41. ILOGIC (Table 42), OLOGIC (Table 43), ISERDES (Table 44), and OSERDES (Table 45) switching characteristics changes. Revised $T_{IDELAY_CLK_MAX}$ and $T_{IDELAYPAT_JIT}$ in Table 46. Revised CLB switching characteristics and added T_{SHCKO} to Table 47 and revised CLB switching characteristics in Table 48 and Table 49. In Table 50, removed $T_{RCKO_RDCOUNT}$ and $T_{RCKO_WRCOUNT}$, removed $T_{RCKO_PARITY_ECC}$: Clock CLK to ECCPARITY in standard ECC mode, revised $T_{RDCK_DI_ECC}/T_{RCKD_DI_ECC}$, $T_{RCKO_POINTERS}$, and revised F_{MAX} and $F_{MAX_CASCADE}$ switching characteristics. Multiple changes to configuration specifications in Table 52. Revised switching characteristics and global clock tree (BUFG) F_{MAX} in Table 53. Revised switching characteristics and I/O clock tree (BUFIO) F_{MAX} in Table 54. Added note 1 to Table 55. Revised the F_{MAX} horizontal clock tree (BUFH) in Table 56. Multiple changes to MMCM specifications in Table 57 including F_{INMAX} and F_{OUTMAX}. Updated switching characteristics in Table 58 through Table 63. Removed T_{DCD_BUFH} and T_{BUFH_SKEW} from Table 64.
06/30/10	1.3	Production release of XC6VCX130T and XC6VCX240T in Table 36 and Table 37. Updated -1 speed grade SDR values in Table 35. Updated BUFIO F_{MAX} specification in Table 54. Added Note 6 to Table 57.
07/28/10	1.4	Production release of XC6VCX75T and XC6VCX195T in Table 36 and Table 37 using ISE 12.2 software with speed file v1.06 using the <i>Speed File Patch</i>. Updated PCI compliance on page 1. Added values to Table 13. In Table 25, update $V_{CMOUTDC}$ equation to $MGTA VTT - DV_{PPOUT}/4$. Updated F_{MAX} in Table 53, Table 54, and Table 56. Updated F_{INMAX} and F_{OUTMAX} in Table 57. Updated values in Table 61, Table 62, and Table 63.
10/14/10	1.5	Moved data sheet to Production status on the first page. Updated speed file with ISE 12.3 software with speed file v1.08 using the <i>Speed File Patch</i>. In Table 51, updated values for T_{DSPCKO_PCOUT}, $CARRYCASCOUT$, $MULTSIGNOUT_PREG$.
02/11/11	1.6	Updated Table 10 to include the industrial range specifications. Added Note 12 to Table 50. Revised T_{BPICCO} values in Table 52. Updated range description for F_{INDUTY} in Table 57 and added note 8. The following revisions are due to specification changes as described in XCN11009, <i>Virtex-6 FPGA: Data Sheet, User Guides, and JTAG ID Updates</i>. In Table 52, updated the values for T_{SMCKW}, T_{SPIDCC}, T_{SPICCM}, and T_{SPICFC}. In Table 57: MMCM Specification, added bandwidth settings to F_{PFDMIN} and added note 1.

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